

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination LEE, EDWARD HIN PONG	
		Examiner Paul D. Kim	Art Unit 3729	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,504,677	01-2003	Han et al.	360/126
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"The effect of track width and topography on composition uniformity of electroplated Permalloy in thin film heads"; Sahami, S.; Lee, H.P.E.; Magnetics, IEEE Transactions on Volume 28, Issue 5, Part 2, Sep 1992; Pages:2103 - 2105.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.